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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Appln. Of: JU

Filed:

December 8, 2005

For:

NONCONTACT CONDUCTIVITY MEASURING INSTRUMENT

Docket:

SHIG CFP03US013

MAIL STOP PCT Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

In connection with the above-entitled matter, Applicant hereby attaches U.S. Patent Office Form PTO-1449, including copies of the references listed therein, which were considered prior to the initial filing, and are discussed in the specification and/or the International Search Report of the corresponding PCT application. A copy of the International Search Report is also enclosed. Where available, English language counterparts and/or abstracts are being provided for the Examiner's convenience. Applicant is not submitting a copy of the U.S. Patent reference as the Office waived the requirement under 37 CFR 1.98(a)(2)(i) on July 11, 2003. The claims in the present application are believed to be patentably distinguished over these references.

This information disclosure statement is being made pursuant to the duty of disclosure imposed by law and formulated in 37 CFR 1.56(A). No representation is made that the information thus disclosed in fact constitutes prior art or that it is the closest prior art, inasmuch as 37 CFR 1.56(A) relies on a materiality concept which depends on subjectivity.

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Docket No. SHIG CFP03US013 Information Disclosure Statement

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In compliance with the requirements of 37 C.F.R. § 1.98(a)(3), as a concise statement of relevance, as it is presently understood by the individual designated in 35 U.S.C. § 1.56(c) most knowledgeable about the content of the information, the undersigned attorney of record submits a copy of the International Search Report by a foreign examiner in which the references were cited. The relevance to the pending U.S. patent application is that the references were cited in a foreign patent application on the same subject matter. However, no independent analysis of the references, the accuracy of the statement of foreign examiner or the claims of the foreign application under the laws of the country or the United States relative to the subject matter claimed in the present application has been made; the present understanding of the contents thereof by the undersigned being based on the foreign examiner's comments submitted therewith.

In the event there are any fee deficiencies or additional fees are payable, please charge them (or credit any overpayment) to our Deposit Account No. 08-1391.

Respectfully submitted

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CERTIFICATE OF EXPRESS MAILING

"Express Mail" Mailing Label No. <u>ED 991925475 US</u>
Date of Deposit December 8, 2005
I hereby certify that this paper and the papers listed thereon are being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above and is addressed to Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.
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			U.S	S. PATENT	DOCUMENTS	3, 2003				
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